

DOE EVMS Metric Specification Legend



1. Process Category

The process per IP2M METRR using EVMS.

2. Metric ID (new, old)

The ID based on the METRR sub-process area. The older ID provided for reference.

3. Method

The method the metric may be analyzed, e.g., software automation or manual.

4. Frequency

Defines how often the metric should be run.

5. Attribute

The specific attribute within the sub-process area.

6. Metric Intent

Defines the intent of the metric.

7. Metric Short Description

A short description to summarize the metric.

8. Metric

Equation used to define and determine the metric result.

X = numerator.

Y = denominator.

9. Max. Threshold

The max. threshold allowed before the metric result is considered a trip, and is either a quantity X or percentage X/Y.

10. Max. Tolerance

The max. tolerance per data item from the data set used in determining the metric result(s).

11. Weight

The weight the metric process carries in determining the overall system score using the IP2M METTR.

12. Needed Artifacts and Data Elements

A list of flat files, artifacts, and specified fields needed to run the metric.

13. Assumptions

A list of assumptions to run the metric.

14. Instructions

The code used to run automated metrics and steps to run manual metrics.

15. Reference(s)

References the metric, attribute, and sub-process requirements. The default reference is the EIA-748. Other reference titles, e.g., PASEG, GAO best practices,...., are stated.

16. Revision Block

A list of the metric revision history.